

**AMENDMENTS TO THE CLAIMS**

Please replace all prior versions of the claims with the following claim listing:

**Claims:**

1. (Currently Amended) A method for testing a device-under-test (DUT), the method comprising ~~the steps of:~~

examining a test data file that includes test data configured to enable testing the DUT, the test data file including a first plurality of data ~~units~~ entries and a second plurality of data ~~units~~ entries, the first plurality of data ~~units~~ entries corresponding to a first plurality of DUT pins, and the second plurality of data ~~units~~ entries corresponding to a second plurality of DUT pins; ~~and~~

determining whether each of the data entries of the test data file corresponds to a pin of the first plurality of DUT pins or to a pin of the second plurality of DUT pins, wherein the first plurality of DUT pins are scan pins and the second plurality of DUT pins are non-scan pins;

separating the first plurality of data ~~units~~ entries from the second plurality of data ~~units~~ entries; wherein

communicating the first plurality of data ~~units~~ entries are communicated to the first plurality of DUT pins; and

communicating the second plurality of data ~~units~~ entries are communicated to the second plurality of DUT pins.

2. (Currently Amended) The method of claim 1, wherein the first plurality of data ~~units~~ entries have at least one different property than the second plurality of data ~~units~~ entries.

3. (Original) The method of claim 2, wherein the at least one different property includes timing complexity.

4. (Original) The method of claim 2, wherein the at least one different property includes vector data volume.

5. (Original) The method of claim 2, wherein the at least one different property includes repetitive data patterns.
6. (Canceled)
7. (Currently Amended) The method of claim 1, further comprising the step of:  
formatting the first plurality of data ~~units~~ entries independently from the second plurality of data ~~units~~ entries.
8. (Original) The method of claim 1, wherein the test data file is one of a STIL (standard test interface language) file and a WGL (waveform generation language) file.
9. (Canceled)
10. (Currently Amended) ~~[[A]] The method for testing a device under test (DUT) of claim 1, the method further comprising the steps of:~~  
~~examining a test data file that includes test data configured to enable testing the DUT, the test data file including a first plurality of data units and a second plurality of data units, the first plurality of data units corresponding to a first plurality of DUT pins, and the second plurality of data units corresponding to a second plurality of DUT pins; and~~  
identifying the first plurality of DUT pins; and  
storing information identifying the first plurality of DUT pins in memory.
11. (Currently Amended) The method of claim 10, further comprising the step of:  
providing the information to a module configured to format the test data file.

12-15. (Canceled)

16. (Currently Amended) A system for testing a device-under-test (DUT), the system comprising:

memory operative to store a test data file that includes test data configured to enable testing the DUT, the test data file including a first plurality of data ~~units~~ entries and a second plurality of data ~~units~~ entries, the first plurality of data ~~units~~ entries corresponding to a first plurality of DUT pins, and the second plurality of data ~~units~~ entries corresponding to a second plurality of DUT pins; and

a processor that is programmed to determine whether each of the data entries of the test data file corresponds to a pin of the first plurality of DUT pins or to a pin of the second plurality of DUT pins, wherein the first plurality of DUT pins are associated with scan pins and the second plurality of DUT pins are associated with non-scan pins, the processor further programmed to separate the first plurality of data ~~units~~ entries from the second plurality of data ~~units~~ entries.

17. (Currently Amended) The system of claim 16, wherein the processor is further programmed to provide the first plurality of data ~~units~~ entries and the second plurality of data ~~units~~ entries to a device configured to format the first plurality of data ~~units~~ entries independently from the second plurality of data ~~units~~ entries.

18. (Canceled)

19. (Currently Amended) ~~[[A]] The system for testing a device under test (DUT) of claim 16, the system comprising:~~

~~memory operative to store a test data file that includes test data configured to enable testing the DUT, the test data file including a first plurality of data units and a second plurality of data units, the first plurality of data units corresponding to a first plurality of DUT pins, and the second plurality of data units corresponding to a second plurality of DUT pins; and~~

wherein ~~[[a]]~~ the processor ~~that~~ is further programmed to identify the first plurality of DUT pins based on information contained in the test data file, and to store information identifying the first plurality of DUT pins in memory.

20. (Original) The system of claim 19, wherein the processor is programmed to provide the information identifying the first plurality of DUT pins to a device configured to format test data.

21. (Canceled)

22. (Currently Amended) A system for testing a device-under-test (DUT), the system comprising:

~~means operative to store~~ for storing a test data file that includes test data configured to enable testing the DUT, the test data file including a first plurality of data ~~units~~ entries and a second plurality of data ~~units~~ entries, the first plurality of data ~~units~~ entries corresponding to a first plurality of DUT pins, and the second plurality of data ~~units~~ entries corresponding to a second plurality of DUT pins;

means for determining whether each of the data entries of the test data file corresponds to a pin of the first plurality of DUT pins or to a pin of the second plurality of DUT pins, wherein the first plurality of DUT pins are scan pins and the second plurality of DUT pins are non-scan pins; and

~~means operative to identify the first plurality of DUT pins based on information contained in the test data file~~

means for separating the first plurality of data entries from the second plurality of data entries, wherein the first plurality of data entries are communicated to the first plurality of DUT pins and the second plurality of data entries are communicated to the second plurality of DUT pins.

23. (New) The system of claim 22, wherein the first plurality of data entries have at least one different property than the second plurality of data entries, the at least one

different property including timing complexity, vector data volume, and repetitive data patterns.

24. (New) The system of claim 22, further comprising:  
means for formatting the first plurality of data entries independently from the second plurality of data entries.

25. (New) The system of claim 22, wherein the test data file is one of a STIL (standard test interface language) file and a WGL (waveform generation language) file.

26. (New) The system of claim 22, wherein the means for formatting is configured to operate in a first timing domain to enable the first plurality of data entries to be provided to the first plurality of DUT pins, and to operate in a second timing domain to enable the second plurality of data entries to be provided to the second plurality of DUT pins, wherein the second timing domain is different from the first timing domain.

27. (New) The system of claim 22, further comprising:  
means for identifying the first plurality of DUT pins and for storing the information identifying the first plurality of DUT pins in the storing means.

28. (New) The method of claim 1, further comprising:  
providing the first plurality of data entries to the first plurality of DUT pins in a first timing domain; and  
providing the second plurality of data entries to the second plurality of DUT pins in a second timing domain;  
wherein the first timing domain is different from the second timing domain.